In Situ Removal of Carbon Contamination from Optics in a VSX Undulator Beamline, BL-13A, Using Oxygen Activated by 0th-Order Synchrotron Radiation

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1 Introduction

When optics are irradiated with synchrotron radiation (SR) in the presence of residual hydrocarbon gases, they are contaminated with carbon [1]. The carbon contamination leads to a significant decrease in the reflectivity in the vacuum ultraviolet and soft X-ray (VSX) region. The photon flux loss in the carbon K-edge region is especially critical because it reduces the quality of experimental data, such as near-edge X-ray absorption fine structure (NEXAFS), resonant photoemission, and resonant soft X-ray emission spectra. In situ SR-activated oxygen cleaning seems to be most advantageous because optics can be cleaned by exposing them to oxygen at 10^{-2} Pa for 15 hours under 0th order SR irradiation [2]. In the present paper we report results of in situ SR-activated oxygen cleaning of optics in a VSX undulator beamline, BL-13A at Photon Factory [3].

2 Experiment

The VSX undulator beamline, BL-13A, has a Monk-Gillieson-type monochromator to cover a wide photonenergy range with a high energy resolution. The details of BL-13A have been described elsewhere [4,5]. Briefly, BL-13A consists of a focusing pre-mirror (M1), a plane mirror (M2), two varied-line-spacing plane gratings (VLSGs, 300 and 1000 lines/mm), an exit slit, and two focusing post-mirrors (M3, 2-m:2-m focusing; M3', 2m:6-m focusing). M1, M2, the VLSGs, M3, and M3' are coated with a gold film with a thickness of 1000 Å or 500 Å. While the SR is vertically reflected by M1, M3, and M3', it is horizontally reflected by M2 and the VLSGs. Dry oxygen with a purity of 99.9% was supplied by using variable leak valves attached to the beamline.

3 Results and Discussion

Figure 1 shows photon intensity spectra measured with the 300-lines/mm VLSG and M3 before and after *in situ* SR-activated oxygen cleaning. The exit slit was fixed at 30 µm. The photon intensity was measured by using a silicon photodiode (AXUV-100, International Radiation Detectors, Inc.). On the basis of the NEXAFS spectra of graphite [6], we ascribed the sharp dip at 285.1 eV to the C $1s \rightarrow \pi^*$ transition of graphite-like carbon with a flaton configuration on M1 and M3, and the sharp dip at 291.5 eV mainly to the C $1s \rightarrow \sigma^*$ transition of graphitelike carbon with a flat-on configuration on M2 and the VLSG. The oxygen pressures in the M1, M2/VLSG, and M3/M3' chambers were in the range 2 × 10⁻⁴ to 6 × 10⁻⁴ Pa, 5×10^{-3} to 1.5×10^{-2} Pa, and 1×10^{-5} to 4×10^{-5} Pa, respectively. M1, M2, the 300-lines/mm VLSG, and M3 were irradiated with 0th-order SR for 20 h. The averaged ring current was 450 mA. The photon intensity dips in the carbon K-edge region reduced to 2-5% after the cleaning. Since these absorption energies are different from those before the cleaning (285.1 and 291.5-291.9 eV), we ascribe them to the carbon contamination in the bulk of the gold film of the optics. The base pressure of the beamline recovered to 10⁻⁷-10⁻⁸ Pa in one day without baking. The beamline can be used without additional commissioning. The interaction of oxygen molecules with photoelectrons emitted from the optics seems to play a dominant role in the removal of carbon contamination. Therefore, in situ SR-activated oxygen cleaning is suitable for optics in undulator beamlines where a high photon flux is easily achieved.

<u>References</u>

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